

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L15	17	((wafer or semiconductor or substrate) (hypothetical or calculated or expected or estimated) diffraction profile).clm.	US-PGPUB	SAME	ON	2008/02/19 15:19
L17	9	((hypothetical or calculated or expected or estimated) diffraction spacing).clm.	US-PGPUB	SAME	ON	2008/02/19 15:20
L19	1	((wafer or semiconductor or substrate) locations diffraction cost).clm.	US-PGPUB	SAME	ON	2008/02/19 15:22
L20	3	((wafer or semiconductor or substrate) locations diffraction (cost or fit or match or tolerance)).clm.	US-PGPUB	SAME	ON	2008/02/19 15:22

2/19/2008 3:24:06 PM

C:\Documents and Settings\Rslomski\My Documents\EAST\Workspaces\10  
663300 Hyprofile wafer sample index.wsp